

Fig 1 RBS-calibrated in situ XRF growth curves for Photo-ALD vs. thermal ALD of Pt at 200°C on O₃-cleaned SiO₂ substrates. The ex situ XRR thickness values measured after 120 ALD cycles are indicated. The horizontal dotted lines represent the Pt loading for which GISAXS data are presented in Figure 3.

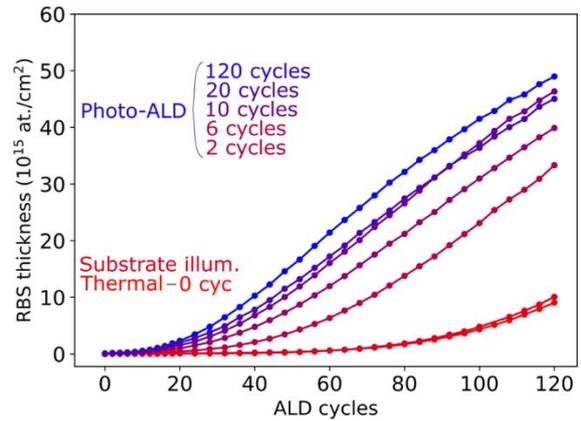


Fig 2 RBS-calibrated in situ XRF growth curves showing the effect of x cycles of Photo-ALD followed by thermal ALD up to a total of 120 cycles. The depositions were done at 175°C on O₃-cleaned SiO₂ substrates.

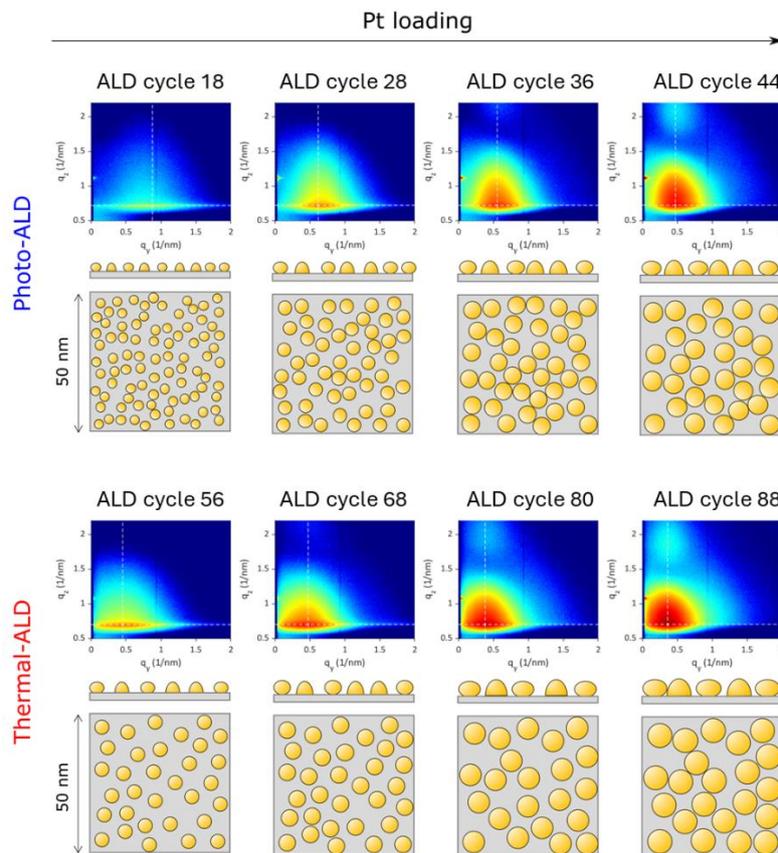


Fig 3 In situ GISAXS patterns corresponding to, from left to right, Pt loadings of ca. 4×10^{15} at/cm², 8×10^{15} at/cm², 13×10^{15} at/cm² and 17×10^{15} at/cm², as obtained from the in-situ XRF data in Figure 1. The ALD cycle number at which this Pt loading is obtained is indicated. The schematics represent the morphological parameters obtained from GISAXS simulations.

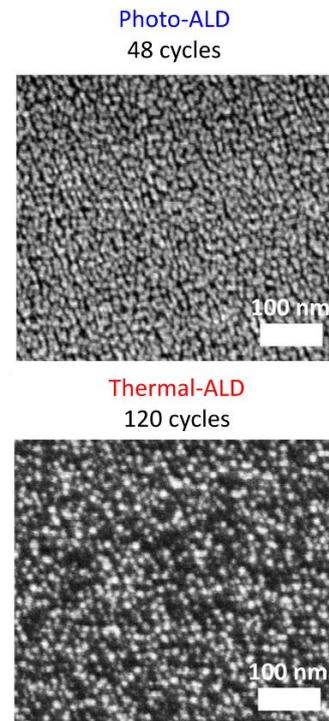


Fig 4 SEM images of samples with a Pt loading of ca. 9×10^{15} at/cm² grown with Photo-ALD vs. thermal ALD at 175°C.